

Notice of References Cited	Application/Control No. 10/600,014		Applicant(s)/Patent Under Reexamination CHATTERJEE ET AL.	
	Examiner SHEW-FEN LIN		Art Unit 2166	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,871,318	03-2005	Wynblatt et al.	715/201
*	B	US-6,519,603	02-2003	Bays et al.	707/102
*	C	US-2004/0150669	08-2004	Sabiers et al.	345/781
	D	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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